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1 Perpendicular media: alloy versus multilayer

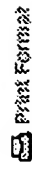
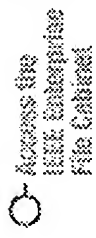
Brucker, C.; Nolan, T.; Bin Lu; Kubota, Y.; Plumer, M.; Pu-Ling Lu; Cronch, R.; Chung-Hee Chang; Chen, D.; Jianping Chen; Michel, R.; Parker, G.; Tabat, N.; Magnetism, IEEE Transactions on , Volume: 39 , Issue: 2 , March 2003
Pages: 673 - 678

[Abstract] [PDF Full-Text (791 KB)] IEEE JNL

2 Developing an aCe solution for two-dimensional strip packing

Dorband, J.E.; Mumford, C.L.; Wang, P.Y.; Parallel and Distributed Processing Symposium, 2004. Proceedings. 18th International , 26-30 April 2004
Pages: 261

[Abstract] [PDF Full-Text (1356 KB)] IEEE CNF



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